

65,536-word × 1-bit High Speed CMOS Static RAM

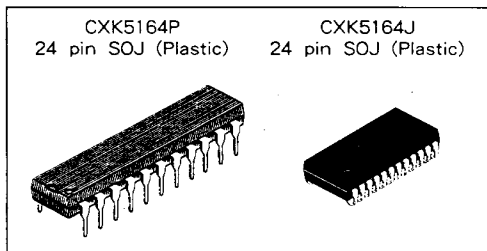
Description

CXK5164P/J are 65,536 bits high speed CMOS static RAMs organized as 65,536 words by 1 bit and operate from a single 5V supply.

These devices have separate Data input and Data Output pins.

Features

- Fast access time :
CXK5164P/J-25 25ns (Max.)
CXK5164P/J-30 30ns (Max.)
CXK5164P/J-35 35ns (Max.)
- Low power operation : 125mW (Typ.)
- Single + 5V supply : +5V ± 10 %
- Fully static memory...No clock or timing strobe required.
- Equal access and cycle time
- Separate I/O pins
- Three-state output
- Directly TTL compatible : All inputs and outputs.
- High density : 300mil 22 pin plastic DIP
300mil 24 pin plastic SOJ



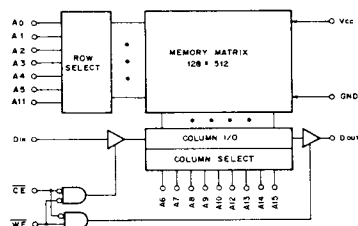
Function

65,536-word × 1-bit static RAM

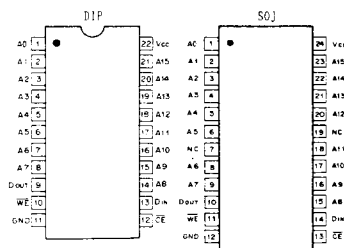
Structure

Silicon gate CMOS IC

Block Diagram



Pin Configuration (Top View)



Pin Description

Symbol	Description
A0 to A15	Address input
Din	Data input
Dout	Data output
CE	Chip enable input
WE	Write enable input
Vcc	+ 5V Power supply
GND	Ground
NC	Non connection

Absolute Maximum Ratings

Item	Symbol	Rating	Unit
Supply voltage	V _{CC}	- 0.5 * to + 7.0	V
Input voltage	V _{IN}	- 0.5 * to V _{CC} + 0.5	V
Operating temperature	T _{opr}	0 to + 70	°C
Storage temperature	T _{stg}	- 55 to + 150	°C
Soldering temperature	T _{solder}	260 ± 10	°C • sec
Voltage applied to output	V _{OUT}	- 0.5 * to V _{CC} + 0.5	V
Allowable power dissipation	P _D	1.0	W

* **Note)** V_{CC}, V_{IN}, V_{OUT} = - 3.5V Min. for pulse width less than 20ns.

Truth Table

CE	WE	Mode	Dout	V _{CC} Current
H	X	Not selected	High Z	I _{SB1} , I _{SB2}
L	H	Read	Data out	I _{CC1} , I _{CC2}
L	L	Write	High Z	I _{CC1} , I _{CC2}

X : "H" or "L"

DC Recommended Operating Conditions

(T_a = 0 to + 70°C, GND = 0V)

Item	Symbol	Min.	Typ.* ¹	Max.	Unit
Supply voltage	V _{CC}	4.5	5.0	5.5	V
Input high voltage	V _{IH}	2.2	—	V _{CC} + 0.3	V
Input low voltage	V _{IL}	- 0.3 * ²	—	0.8	V

Note) * 1. V_{CC} = 25°C

* 2. V_{IL} = - 3.0V Min. for pulse width less than 20ns.

Electrical Characteristics

DC and operating characteristics

(V_{CC} = 5V ± 10 %, GND = 0V, T_a = 0 to +70 °C)

Item	Symbol	Test conditions	- 25/30/35			Unit
			Min.	Typ.	Max.	
Input leakage current	I _{LI}	V _{IN} = GND to V _{CC}	- 1	—	1	μA
Output leakage current	I _{LO}	$\overline{CE} = V_{IH}$ or $\overline{WE} = V_{IL}$ V _{I/O} = GND to V _{CC}	- 1	—	1	μA
Operating power supply current	I _{CC1}	$\overline{CE} = V_{IL}$, I _{OUT} = 0mA V _{IN} = V _{IH} /V _{IL}	—	25	45	mA
Average operating current	I _{CC2}	Cycle = Min, Duty = 100 % I _{OUT} = 0mA	—	60	90	mA
Standby current	I _{SB1}	$\overline{CE} \geq V_{CC} - 0.2V$, V _{IN} ≥ V _{CC} - 0.2V or V _{IN} ≤ 0.2V	—	—	1	mA
	I _{SB2}	$\overline{CE} = V_{IH}$	—	15	30	mA
Output high voltage	V _{OH}	I _{OH} = - 4.0mA	2.4	—	—	V
Output low voltage	V _{OL}	I _{OL} = 8.0mA	—	—	0.4	V

*Note) V_{CC} = 5.0V, T_a = 25 °C

I/O capacitance

(T_a = 25 °C, f = 1MHz)

Item	Symbol	Test conditions	Min.	Max.	Unit
Input capacitance	C _{IN}	V _{IN} = 0V	—	7	pF
Output capacitance	C _{OUT}	V _{OUT} = 0V	—	7	pF

Note) This parameter is sampled and is not 100 % tested.

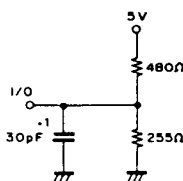
AC characteristics

● AC test conditions

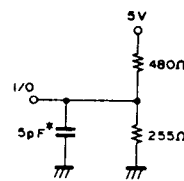
(V_{CC} = 5V ± 10 %, T_a = 0 to +70 °C)

Item	Conditions
Input pulse high level	V _{IH} = 3.0V
Input pulse low level	V _{IL} = 0V
Input rise time	t _r = 5ns
Input fall time	t _f = 5ns
Input and output timing reference level	1.5V
Output load	Fig. 1

Output Load (1)



Output Load (2)*2



*1. Including scope and jig

*2. For t_{LZ}, t_{HZ}, t_{OW}, t_{WHZ}

Fig. 1

● Read cycle

Item	Symbol	- 25		- 30		- 35		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read cycle time	t _{RC}	25	—	30	—	35	—	ns
Address access time	t _{AA}	—	25	—	30	—	35	ns
Chip enable access time ($\overline{CE}$)	t _{CO}	—	25	—	30	—	35	ns
Output hold from address change	t _{OH}	5	—	5	—	5	—	ns
Chip enable to output in low Z ($\overline{CE}$)	t _{LZ} *	5	—	5	—	5	—	ns
Chip disable to output in high Z	t _{HZ} *	0	10	0	15	0	15	ns
Chip enable to power up time	t _{PU}	0	—	0	—	0	—	ns
Chip disable to power down time	t _{PD}	—	20	—	25	—	25	ns

* **Note)** Transition is measured $\pm 200\text{mV}$ from steady voltage with specified loading in Fig. 1.
This parameter is sampled and is not 100% tested.

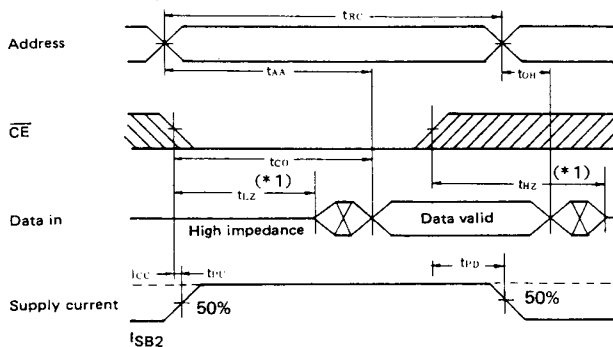
● Write cycle

Item	Symbol	- 25		- 30		- 35		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Write cycle time	t _{WC}	25	—	30	—	35	—	ns
Address valid to end of write	t _{AW}	20	—	25	—	30	—	ns
Chip enable to end of write	t _{CW}	20	—	25	—	30	—	ns
Data to write time overlap	t _{DW}	12	—	15	—	15	—	ns
Data hold from write time	t _{DH}	0	—	0	—	0	—	ns
Write pulse width	t _{WP}	20	—	25	—	30	—	ns
Address setup time	t _{AS}	0	—	0	—	0	—	ns
Write recovery time	t _{WR}	0	—	0	—	0	—	ns
Output active from end of write	t _{OW} *	5	—	5	—	5	—	ns
Write to output in high Z	t _{WHZ} *	0	10	0	10	0	15	ns

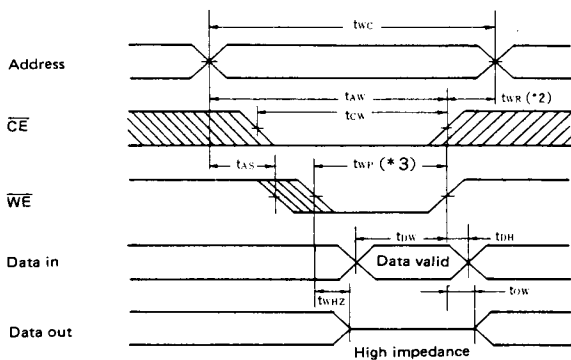
* **Note)** Transition is measured $\pm 200\text{mV}$ from steady voltage with specified loading in Fig. 1.
This parameter is sampled and is not 100% tested.

Timing Waveform

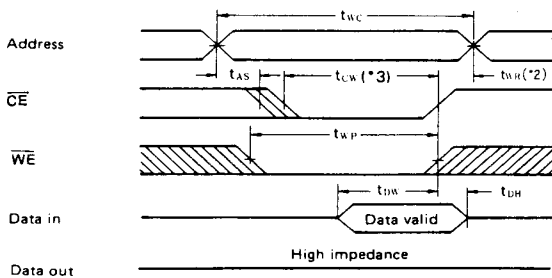
• Read cycle : $\overline{WE} = V_{IH}$



• Write cycle (1) : $\overline{WE}$ control



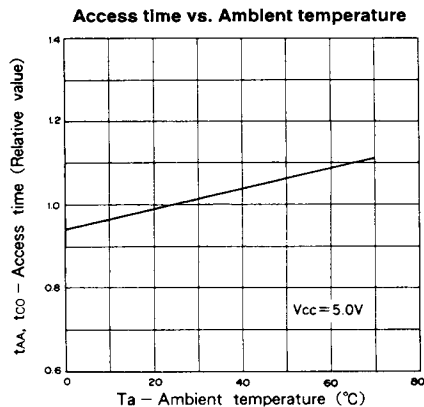
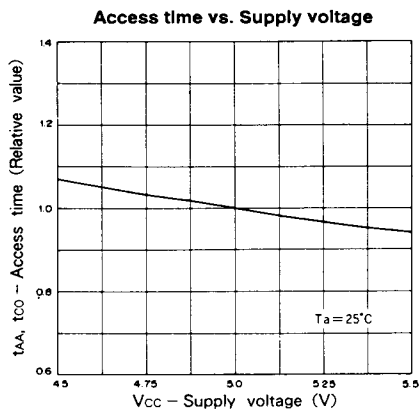
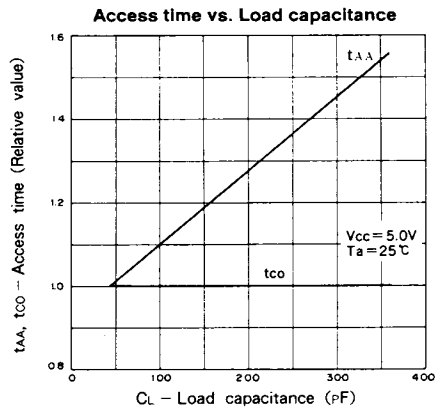
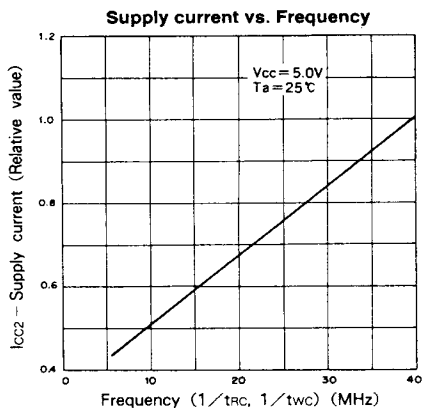
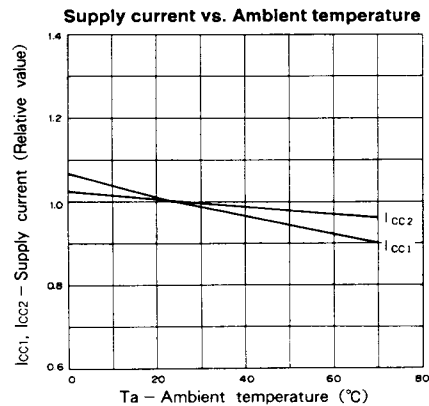
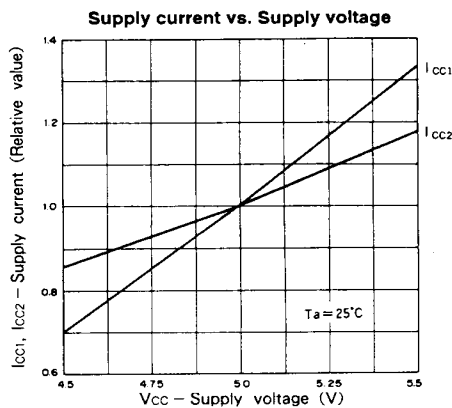
• Write cycle (2) : $\overline{CE}$ control



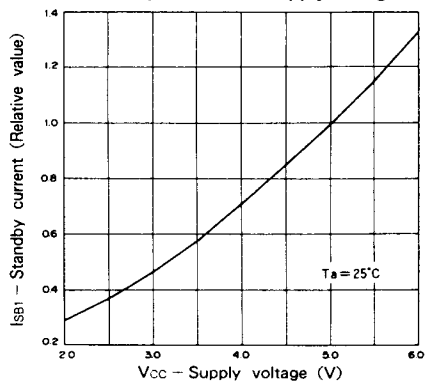
* Note)

1. At any conditions, t_{HZ} is less than t_{LZ} .
2. t_{WR} is measured from the earlier of $\overline{CE}$ or $\overline{WE}$ going high to the end of write cycle.
3. A write occurs during the low overlap of $\overline{CE}$ and $\overline{WE}$.

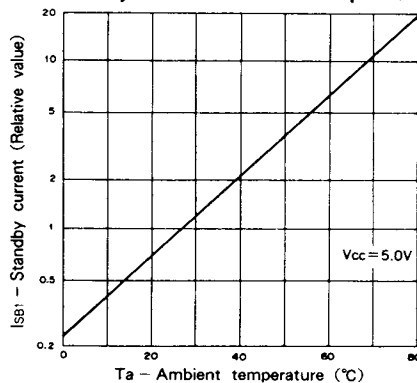
Example of Representative Characteristics



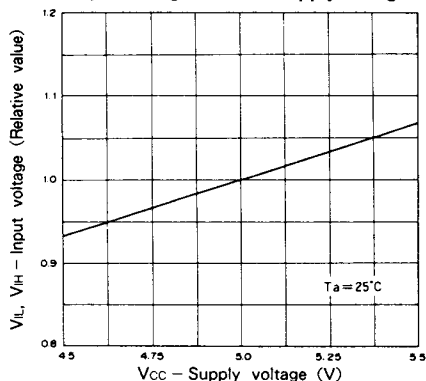
Standby current vs. Supply voltage



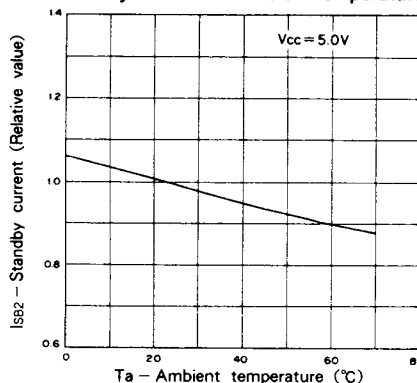
Standby current vs. Ambient temperature



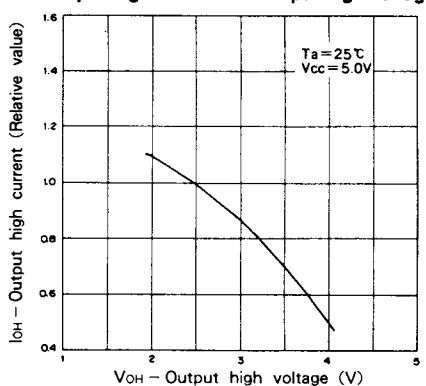
Input voltage level vs. Supply voltage



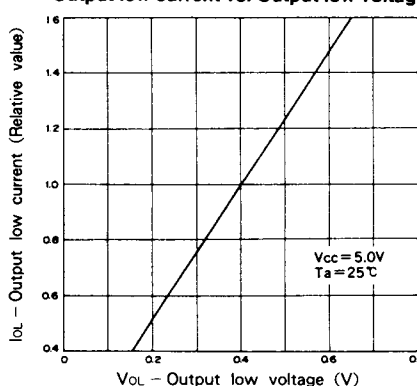
Standby current vs. Ambient temperature



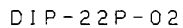
Output high current vs. Output high voltage



Output low current vs. Output low voltage



CXK5164P 22 pin DIP (Plastic) 300mil 1.3g



CXK5164J 24 pin SOJ (Plastic) 300mil 0.7g

